

REMARKS

Favorable reconsideration of this application is requested in view of the above amendments and the following remarks.

The claims have been renumbered as suggested by the Examiner to correct an editorial error. Claims 1-19 are pending, with claims 12, 13, 16, and 17 being withdrawn from consideration. Claims 1, 2, 12 (withdrawn), 13 (withdrawn), 14, 15, 16 (withdrawn), 17 (withdrawn), 18, and 19 are independent. Applicants request that the non-elected claims be maintained and reinstated if amended to track allowed subject matter of the elected claims.

Claims 1, 2, 14, 15, 18, and 19 are amended. The revisions to claims 1, 14, 15, 18, and 19 are supported, for example, at original claim 2, and at page 6, lines 14-30 in the specification. Claim 11 has been canceled without prejudice to or disclaimer of the subject matter recited therein.

Initially, Applicants would like to thank the Examiner for the indication that the application contains allowable subject matter, and that claims 2 and 4-10 are allowable over the prior art of record. Claim 2 has been rewritten in independent form with each of the limitations of claim 1. Therefore, Applicants respectfully submit that claims 2 and 4-10 are in condition for allowance.

Objections to the Drawings

The Examiner has objected to the form of Figures 1, 14, 16, 17 and 18. Those Figures have been amended in accordance with the Examiner's request. Replacement sheets t3 and annotated sheets showing the proposed changes are included herewith.

Claim rejections - 35 U.S.C. § 103

Claims 1, 3, 11, 14, 15, 18, and 19 stand rejected as being unpatentable over U.S. Patent No. 5,673,232 (Furutani) in view of 6,031,397 (Banba). Applicants respectfully traverse this rejection; however, claim 11 has been canceled, rendering the rejection moot with respect to that claim.

Independent claim 1 is directed to a semiconductor integrated circuit. A voltage detection part comprises a measuring voltage generation circuit, which receives an output voltage from the charge pump part and generates a measuring voltage based on the output voltage from the charge pump part. The voltage detection part also comprises a comparator,

coupled to receive a ground voltage as a reference voltage, for comparing the measuring voltage with the ground voltage.

Furutani is directed to a semiconductor memory device. As acknowledged by the Examiner, however, Furutani does not teach or suggest a voltage detection part comprising a measuring voltage generation circuit and comparator as recited in claim 1.

Banba does not remedy the deficiencies of Furutani. Banba is directed to a negative voltage detection circuit. Banba does not teach or suggest that a comparator compares a measuring voltage with a ground voltage. Instead, Banba teaches that a reference voltage (V_{ref}) can be used. However, there is no suggestion that the reference voltage is a ground voltage. Moreover, the embodiments disclosed by Banba suggest otherwise. For example, Figure 5 clearly teaches that the reference voltage has to be a positive voltage not lower than a threshold voltage of the transistor TN1. Accordingly, Banba does not teach or suggest the use of a ground voltage as claimed.

Since neither of the cited references teaches or discloses at least the above-described features, Applicants submit that claim 1 is allowable over the cited reference.

Claim 3 depends from claim 1. Therefore, claim 3 is believed allowable for at least the reason that it is dependent upon an allowable base claim.

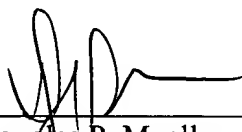
Independent claims 14, 15, 18, and 19 each includes the features recited above with respect to claim 1. Therefore, each of those claims is believed allowable over the cited references for at least the same reasons discussed above with respect to claim 1.

In view of the above, favorable reconsideration in the form of a notice of allowance is requested.

Respectfully submitted,

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